Data sheet acquired from Cypress Semiconductor Corporation.
Data sheet modified to remove devices not offered.

TEXAS INSTRUMENTS

CY54/74FCT273T

8-Bit Register

SCCS020 - March 1995 - Revised February 2000

Features

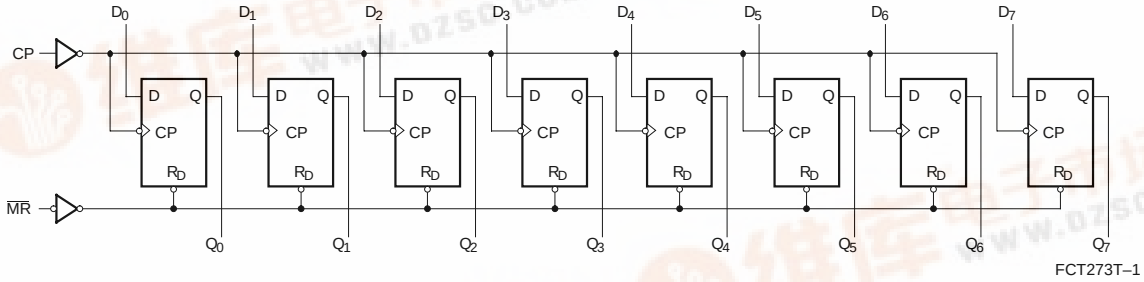
- **Function, pinout, and drive compatible with FCT and F logic**
- **FCT-C speed at 5.8 ns max. (Com'l)**
  FCT-A speed at 7.2 ns max. (Com'l)
- **Reduced V_{OH} (typically = 3.3V) versions of equivalent FCT functions**
- **Edge-rate control circuitry for significantly improved noise characteristics**
- **Power-off disable feature**
- **Matched rise and fall times**
- **ESD > 2000V**
- **Fully compatible with TTL input and output logic levels**
- **Extended commercial range of –40°C to +85°C**
- **Sink current 64 mA (Com'l), 32 mA (Mil)**
  Source current 32 mA (Com'l), 12 mA (Mil)

Functional Description

The FCT273T consists of eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered clock (CP) and master reset (MR) load and reset all flip-flops simultaneously. The FCT273T is an edge-triggered register. The state of each D input (one set-up time before the LOW-to-HIGH clock transition) is transferred to the corresponding flip-flop's Q output. All outputs will be forced LOW by a low voltage level on the $\overline{MR}$ input.

The outputs are designed with a power-off disable feature to allow for live insertion of boards.

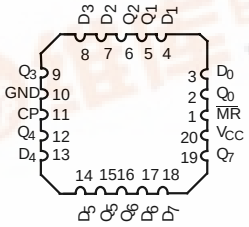
Logic Block Diagram



FCT273T–1

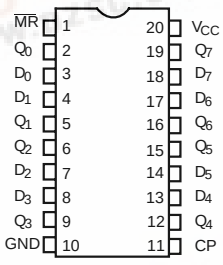
Pin Configurations

LCC
Top View



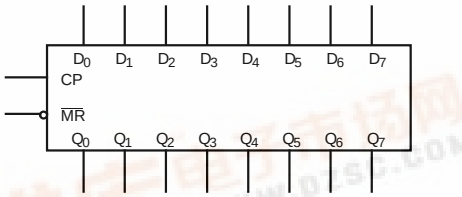
FCT273T–2

DIP/SOIC/QSOP
Top View



FCT273T–3

Logic Symbol



FCT273T–4

Function Table[1]

Operating Mode	Inputs			Output
	$\overline{MR}$	CP	D	Q
Reset (clear)	L	X	X	L
Load '1'	H	⌐	h	H
Load '0'	H	⌐	l	L

Note:

1. H = HIGH Voltage Level steady state
   h = HIGH Voltage Level one set-up time prior to LOW-to-HIGH clock transition
   L = LOW Voltage Level steady state
   l = LOW Voltage Level one set-up time prior to the LOW-to-HIGH transition
   X = Don't Care
   ⌐ = LOW-to-HIGH clock transition

Maximum Ratings[2, 3]

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature .....–65°C to +150°C

Ambient Temperature with Power Applied.....–65°C to +135°C

Supply Voltage to Ground Potential.....–0.5V to +7.0V

DC Input Voltage .....–0.5V to +7.0V

DC Output Voltage .....–0.5V to +7.0V

DC Output Current (Maximum Sink Current/Pin).....120 mA

Power Dissipation 0.5W

Static Discharge Voltage.....>2001V (per MIL-STD-883, Method 3015)

Operating Range

Range	Range	Ambient Temperature	V_{CC}
Commercial	All	–40°C to +85°C	5V ± 5%
Military[4]	All	–55°C to +125°C	5V ± 10%

Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions		Min.	Typ.[5]	Max.	Unit
V_{OH}	Output HIGH Voltage	V_{CC}=Min., I_{OH}=–32 mA	Com'l	2.0			V
		V_{CC}=Min., I_{OH}=–15 mA	Com'l	2.4	3.3		V
		V_{CC}=Min., I_{OH}=–12 mA	Mil	2.4	3.3		V
V_{OL}	Output LOW Voltage	V_{CC}=Min., I_{OL}=64 mA	Com'l		0.3	0.55	V
		V_{CC}=Min., I_{OL}=32mA	Mil		0.3	0.55	V
V_{IH}	Input HIGH Voltage			2.0			V
V_{IL}	Input LOW Voltage					0.8	V
V_H	Hysteresis[6]	All inputs			0.2		V
V_{IK}	Input Clamp Diode Voltage	V_{CC}=Min., I_{IN}=–18 mA			–0.7	–1.2	V
I_I	Input HIGH Current	V_{CC}=Max., V_{IN}=V_{CC}				5	µA
I_{IH}	Input HIGH Current	V_{CC}=Max., V_{IN}=2.7V				±1	µA
I_{IL}	Input LOW Current	V_{CC}=Max., V_{IN}=0.5V				±1	µA
I_{OS}	Output Short Circuit Current[7]	V_{CC}=Max., V_{OUT}=0.0V		–60	–120	–225	mA
I_{OFF}	Power-Off Disable	V_{CC}=0V, V_{OUT}=4.5V				±1	µA

Capacitance[6]

Parameter	Description	Typ.[5]	Max.	Unit
C_{IN}	Input Capacitance	5	10	pF
C_{OUT}	Output Capacitance	9	12	pF

Notes:

2. Unless otherwise noted, these limits are over the operating free-air temperature range.
3. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.
4. T_A is the "instant on" case temperature
5. Typical values are at V_{CC}=5.0V, T_A=+25˚C ambient.
6. This parameter is specified but not tested.
7. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

Power Supply Characteristics

Parameter	Description	Test Conditions	Typ.[5]	Max.	Unit
I_{CC}	Quiescent Power Supply Current	V_{CC}=Max., $V_{IN} \le 0.2V$, $V_{IN} \ge V_{CC}$-0.2V	0.1	0.2	mA
ΔI_{CC}	Quiescent Power Supply Current (TTL inputs HIGH)	V_{CC}=Max., V_{IN}=3.4V, f_1=0, Outputs Open [8]	0.5	2.0	mA
I_{CCD}	Dynamic Power Supply Current[9]	V_{CC}=Max., One Bit Toggling, 50% Duty Cycle, Outputs Open, $\overline{MR}$=V_{CC}, $V_{IN} \le 0.2V$ or $V_{IN} \ge V_{CC}$-0.2V	0.06	0.12	mA/MHz
I_C	Total Power Supply Current[10]	V_{CC}=Max., f_0=10 MHz, 50% Duty Cycle, Outputs Open, One Bit Toggling at f_1=5 MHz, $\overline{MR}$=V_{CC}, $V_{IN} \le 0.2V$ or $V_{IN} \ge V_{CC}$-0.2V	0.7	1.4	mA
		V_{CC}=Max., f_0=10 MHz, 50% Duty Cycle, Outputs Open, One Bit Toggling at f_1=5 MHz, $\overline{MR}$=V_{CC}, V_{IN}=3.4V or V_{IN}=GND	1.2	3.4	mA
		V_{CC}=Max., f_0=10 MHz, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at f_1=2.5MHz, $\overline{MR}$=V_{CC}, $V_{IN} \le 0.2V$ or $V_{IN} \ge V_{CC}$-0.2V	1.6	3.2[11]	mA
		V_{CC}=Max., f_0=10 MHz, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at f_1=2.5 MHz, $\overline{MR}$=V_{CC}, V_{IN}=3.4V or V_{IN}=GND	3.9	12.2[11]	mA

Notes:

8. Per TTL driven input (V_{IN}=3.4V); all other inputs at V_{CC} or GND.
9. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
10. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
    $I_C = I_{CC}+\Delta I_{CC} D_H N_T + I_{CCD}(f_0/2 + f_1 N_1)$
    I_{CC} = Quiescent Current with CMOS input levels
    ΔI_{CC} = Power Supply Current for a TTL HIGH input (V_{IN}=3.4V)
    D_H = Duty Cycle for TTL inputs HIGH
    N_T = Number of TTL inputs at D_H
    I_{CCD} = Dynamic Current caused by an input transition pair (HLH or LHL)
    f_0 = Clock frequency for registered devices, otherwise zero
    f_1 = Input signal frequency
    N_1 = Number of inputs changing at f_1
    All currents are in milliamps and all frequencies are in megahertz.
11. Values for these conditions are examples of the I_{CC} formula. These limits are specified but not tested.

Switching Characteristics Over the Operating Range[12]

Parameter	Description	FCT273T		FCT273AT				Unit	Fig. No.[13]
		Commercial		Military		Commercial			
		Min.	Max.	Min.	Max.	Min.	Max.		
t_{PLH} t_{PHL}	Propagation Delay Clock to Output	2.0	13.0	2.0	8.3	2.0	7.2	ns	1, 5
t_{PLH} t_{PHL}	Propagation Delay $\overline{MR}$ to Output	2.0	13.0	2.0	8.3	2.0	7.2	ns	1, 6
t_S	Set-Up Time HIGH or LOW D to Clock	2.0		2.0		2.0		ns	4
t_H	Hold Time HIGH or LOW D to Clock	1.5		1.5		1.5		ns	4
t_W	Clock Pulse Width HIGH or LOW	6.0		6.0		6.0		ns	5
t_W	$\overline{MR}$ Pulse Width LOW	6.0		6.0		6.0		ns	6
t_{REC}	Recovery Time $\overline{MR}$ to Clock	2.0		2.5		2.0		ns	6

Parameter	Description	FCT273CT		Unit	Fig. No.[13]
		Commercial			
		Min.	Max.		
t_{PLH} t_{PHL}	Propagation Delay Clock to Output	2.0	5.8	ns	1, 5
t_{PLH} t_{PHL}	Propagation Delay $\overline{MR}$ to Output	2.0	6.1	ns	1, 6
t_S	Set-Up Time HIGH or LOW D to Clock	2.0		ns	4
t_H	Hold Time HIGH or LOW D to Clock	1.5		ns	4
t_W	Clock Pulse Width HIGH or LOW	6.0		ns	5
t_W	$\overline{MR}$ Pulse Width LOW	6.0		ns	6
t_{REC}	Recovery Time $\overline{MR}$ to Clock	2.0		ns	6

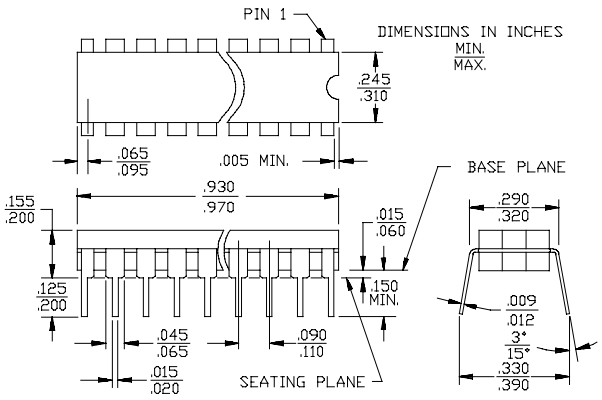
Ordering Information

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
5.8	CY74FCT273CTQCT	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT273CTSOC/SOCT	S5	20-Lead (300-Mil) Molded SOIC	
7.2	CY74FCT273ATQCT	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT273ATSOC/SOCT	S5	20-Lead (300-Mil) Molded SOIC	
8.3	CY54FCT273ATLMB	L61	20-Square Leadless Chip Carrier	Military
	CY54FCT273ATDMB	D6	20-Lead (300-Mil) CerDIP	
13.0	CY74FCT273TQCT	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT273TSOC/SOCT	S5	20-Lead (300-Mil) Molded SOIC	

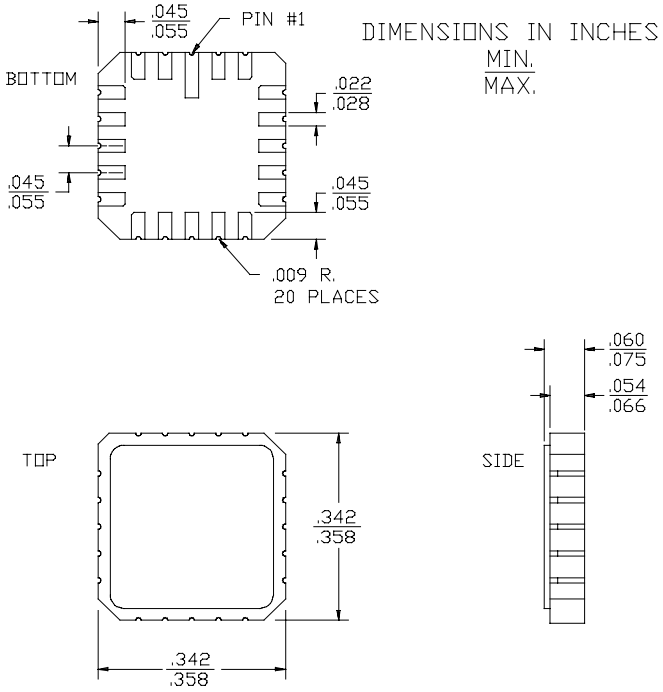
Notes:
12. Minimum limits are specified but not tested on Propagation Delays.
13. See “Parameter Measurement Information” in the General Information section.

Package Diagrams

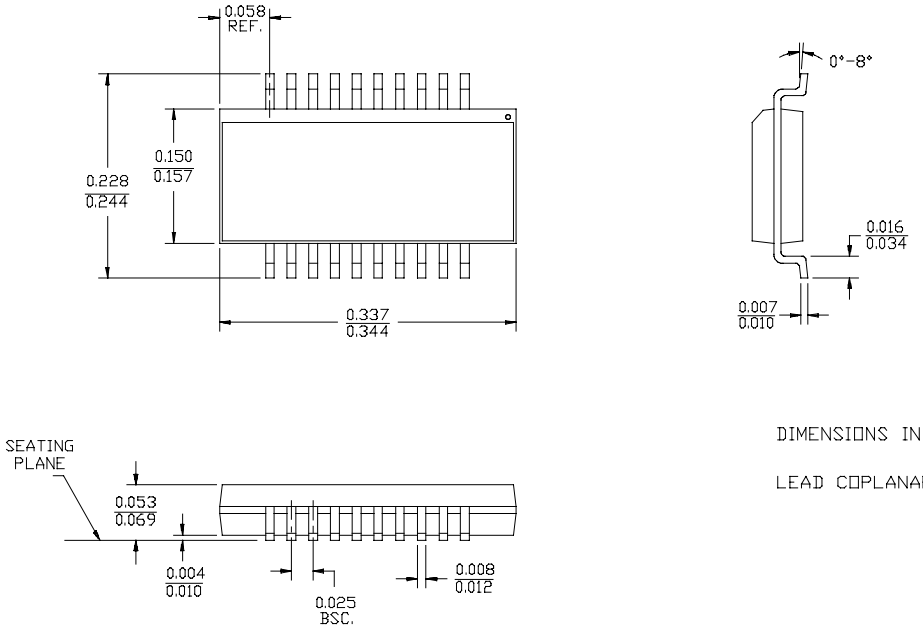
20-Lead (300-Mil) CerDIP D6
MIL-STD-1835 D- 8 Config.A



20-Pin Square Leadless Chip Carrier L61
MIL-STD-1835 C-2A

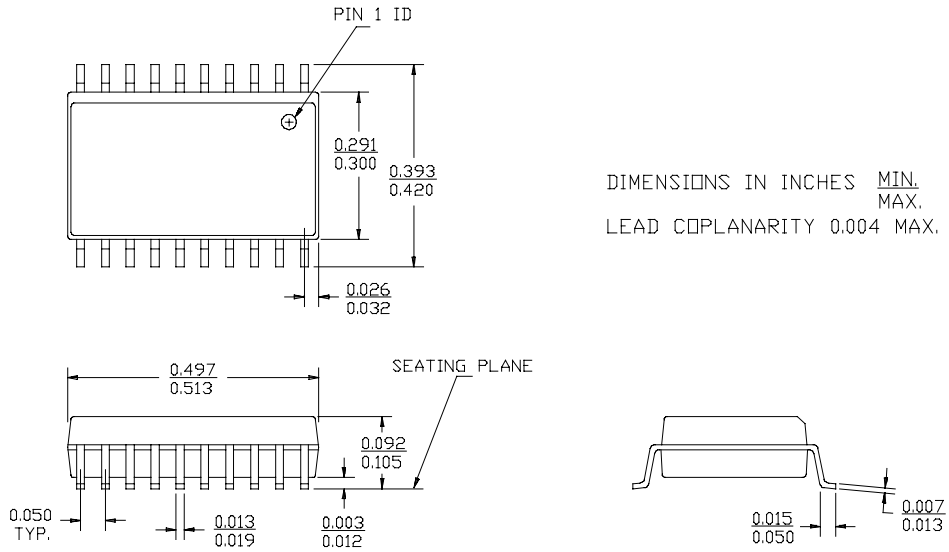


20-Lead Quarter Size Outline Q5



Package Diagrams (continued)

20-Lead (300-Mil) Molded SOIC S5



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.